<i>₹</i> . ♦	Application No.	Applicant(s)	_
	10/743,768	YO, SEIJI	
Notice of Allowability	Examiner	Art Unit	_
	DUC Q. DINH	2629	
The MAILING DATE of this communication ap All claims being allowable, PROSECUTION ON THE MERITS I herewith (or previously mailed), a Notice of Allowance (PTOL-8 NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT of the Office or upon petition by the applicant. See 37 CFR 1.3	pears on the cover sheet wind S (OR REMAINS) CLOSED in the same should be sh	ith the correspondence address n this application. If not included unication will be mailed in due course. THIS	e
1. This communication is responsive to <u>09/08/06</u> .	·		
2. ☑ The allowed claim(s) is/are <u>1-5</u> .			
3. ☐ Acknowledgment is made of a claim for foreign priority a) ☐ All b) ☐ Some* c) ☐ None of the: 1. ☐ Certified copies of the priority documents ha 2. ☐ Certified copies of the priority documents ha 3. ☐ Copies of the certified copies of the priority of International Bureau (PCT Rule 17.2(a)). * Certified copies not received: Applicant has THREE MONTHS FROM THE "MAILING DATE	ve been received. ve been received in Application	on No d in this national stage application from the	
noted below. Failure to timely comply will result in ABANDON THIS THREE-MONTH PERIOD IS NOT EXTENDABLE. 4. A SUBSTITUTE OATH OR DECLARATION must be sub-	NMENT of this application.		
INFORMAL PATENT APPLICATION (PTO-152) which g			
5. CORRECTED DRAWINGS (as "replacement sheets") m	ust be submitted.		
(a) ☐ including changes required by the Notice of Draftspe	erson's Patent Drawing Review	w (PTO-948) attached	
1) 🗌 hereto or 2) 🔲 to Paper No./Mail Date	_·		
(b) ☐ including changes required by the attached Examine Paper No./Mail Date Identifying indicia such as the application number (see 37 CFR)			
each sheet. Replacement sheet(s) should be labeled as such in			
6. DEPOSIT OF and/or INFORMATION about the department attached Examiner's comment regarding REQUIREMEN			
Attachment(s) 1. ☑ Notice of References Cited (PTO-892)	5. \(\sum \) Notice of In	formal Patent Application	
2. Notice of Draftperson's Patent Drawing Review (PTO-948) 6. 🗌 Interview S	ummary (PTO-413),	
3. Information Disclosure Statements (PTO/SB/08),		/Mail Date Amendment/Com/ngnt	
Paper No./Mail Date <u>See Continuation Sheet</u> 4. Examiner's Comment Regarding Requirement for Deposit of Biological Material	8. ⊠ Examiner's	Statement of Reasons for Allowance	
		RICHARD HJERPE SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2600	

U.S. Patent and Trademark Office PTOL-37 (Rev. 08-06) Continuation of Attachment(s) 3. Information Disclosure Statements (PTO/SB/08), Paper No./Mail Date: 3/2/06;12/23/05;12/24/03.

Application/Control Number: 10/743,768

Art Unit: 2629

DETAILED ACTION

1. This Office Action is responsive for the Applicant Response to the Election/Restriction Requirement file on September 8, 2006.

2. Applicant's election without traverse of claims 1-5 in the reply filed on September 8, 2006 is acknowledged.

EXAMINER'S AMENDMENT

3. The application has been amended as follows:

This application is in condition for allowance except for the presence of claims 6-9 directed to an invention non-elected without traverse.

Accordingly, claims 6-9 been cancelled.

Reason for Allowance

- 4. Claims 1-5 are allowable.
- 5. The following is an examiner's statement of reasons for allowance:

The present invention related to a liquid crystal display having subpixel driven in a binary manner. The independent claim 1 identifies the uniquely distinct features

"Wherein,

each of said plurality of sub-pixels includes a sub-pixel electrode, a first thin film layer transistor, and a second thin film transistor, and is connected to a common line to which a predetermined voltage is applied,

a source electrode and a drain electrode of the second thin film layer transistor are connected to a drain electrode of the first thin film transistor and the sub-pixel electrode,

respectively, and a source electrode of the first thin film layer transistor is connected to the common line, and

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a gate electrode of the first thin film layer transistor is connected to one of said plurality of scanning signal lines or one of said plurality of data signal lines, and a gate electrode of the second thin film layer transistor is connected to one of said plurality of scanning signal lines or one of said plurality of data signal lines, which is not connected to the gate electrode of the first thin film layer transistor".

The closest prior arts of Tsuboyama et al. (U.S Patent No. 6,714,212) and Hiyama et al. (U.S Patent No. 6,909,442) show similar systems which disclose subpixels for liquid crystal display devices, but either singularly or in combination, fail to anticipate or render above quoted limitations obvious.

6. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

7. Any inquiry concerning this communication or earlier communications from the examiner should be directed to DUC Q DINH whose telephone number is (571) 272-7686. The examiner can normally be reached on Mon-Fri from 8:00.AM-4:00.PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Richard Hjerpe can be reached on (571) 272-7691. The fax phone number for the organization where this application or proceeding is assigned is **571-273-8300**.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

DUC Q DINH Examiner Art Unit 2629

DQD November 20, 2006

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